

L Number	Hits	Search Text	DB	Time stamp
-	7	valence adj band and conduction adj band and semiconductor same testing	USOCR	2003/06/05 17:10
-	1	2790952.URPN.	USPAT	2002/12/06 18:42
-	6	3493767.URPN.	USPAT	2002/12/06 18:43
-	4	valence adj band and conduction adj band and semiconductor same testing	EPO; JPO; DERWENT; IBM_TDB	2002/12/06 18:47
-	39	valence adj band and conduction adj band and semiconductor same testing	USPAT;	2002/12/06 19:25
-	8	(valence adj band and conduction adj band and semiconductor same testing) and 324/\$.ccls.	US-PGPUB USPAT; US-PGPUB	2002/12/06 19:26
-	0	20020021141.URPN.	USPAT	2002/12/06 19:39
-	3	("4051437" "4287473" "4333051").PN.	USPAT	2002/12/06 19:40
-	14	4599558.URPN.	USPAT	2002/12/06 19:41
-	9	measuring same conduction same valence same gap same band	USOCR	2002/12/06 20:02
-	2	measuring same conduction same valence same gap same band	EPO; JPO; DERWENT; IBM_TDB	2002/12/06 20:02
-	7	measuring same conduction same valence same gap same band	USPAT;	2002/12/06 20:04
-	1	4953983.pn.	USPAT; US-PGPUB	2003/06/04 13:27
-	2	(("4393348") or ("0433051")).PN.	USPAT; US-PGPUB	2003/06/04 13:28
-	2	(("4393348") or ("4333051")).PN.	USPAT; US-PGPUB	2003/06/04 14:16
-	6	defect\$4 with valance adj band	USPAT; US-PGPUB	2003/06/04 14:23
-	3	(defect\$4 with valence adj band) and 324/\$.ccls.	USPAT; US-PGPUB	2003/06/04 14:27
-	100	defect\$4 with valence adj band	USPAT; US-PGPUB	2003/06/04 14:28
-	0	"6239606"	USOCR	2003/06/05 17:11
-	2	"6239606"	USPAT; US-PGPUB	2003/06/05 17:11

-	4	("4417204" "4820975" "5177528" "5525912").PN.	USPAT	2003/10/30 13:31
-	4	("4417204" "4820975" "5177528" "5525912").PN.	USPAT	2003/10/30 14:18
-	1	"5254939".PN.	USPAT	2003/10/30 14:18
-	7	5525912.URPN.	USPAT	2003/10/30 14:19
-	10	Nidec-Read adj Corporation	USPAT; US-PGPUB	2003/10/30 14:21
-	5	("4677474" "4820975" "4934064" "4985676" "5644245").PN.	USPAT	2003/10/30 14:27
-	0	6356093.URPN.	USPAT	2003/10/30 14:27
-	1	"6411079"	USPAT; US-PGPUB	2003/12/30 16:05
-	4	("4417204" "4820975" "5177528" "5525912").PN.	USPAT	2003/12/30 16:04
-	0	"11151270"	USPAT; US-PGPUB	2003/12/30 16:05
-	2	"11151270"	EPO; JPO; DERWENT;	2003/12/30 16:05
-	27	702/80.cccls.	IBM TDB USPAT; US-PGPUB	2003/12/30 16:50
-	464	714/719.cccls.	USPAT; US-PGPUB	2003/12/30 16:50
-	348	714/719.cccls. and writing	USPAT; US-PGPUB	2003/12/30 16:52
-	0	(714/719.cccls. and writing) and wavelength	USPAT; US-PGPUB	2003/12/30 16:53
-	2	714/735-736.cccls. and wavelength	USPAT; US-PGPUB	2003/12/30 17:09
-	11	("3614451" "3916306" "4114116" "4124280" "4218142" "4242635" "4365310" "4403834" "4408884" "4504921" "4603293").PN.	USPAT	2003/12/30 16:55
-	9	4683420.URPN.	USPAT	2003/12/30 16:58
-	873	324/96.cccls.	USPAT; US-PGPUB	2003/12/30 17:09
-	295	324/96.cccls. and wavelength	USPAT; US-PGPUB	2003/12/30 17:09
-	4	(324/96.cccls. and wavelength) and valence	USPAT; US-PGPUB	2003/12/30 17:10
-	36	(324/96.cccls. and wavelength) and writ\$4	USPAT; US-PGPUB	2003/12/30 17:15
-	159	test\$4 with cell same wavelength and memory	USPAT; US-PGPUB	2003/12/30 17:16
-	7	test\$4 with cell with memory same wavelength	USPAT; US-PGPUB	2003/12/30 17:23
-	1652	(test\$4 with cell with memory).clm.	USPAT; US-PGPUB	2003/12/30 17:34
-	0	((test\$4 with cell with memory).clm.) and 324/96.cccls.	USPAT; US-PGPUB	2003/12/30 17:24
-	17	((test\$4 with cell with memory).clm.) and 324/765.cccls.	USPAT; US-PGPUB	2003/12/30 17:24
-	19	(test\$4 with cell with memory and electron).clm.	USPAT; US-PGPUB	2003/12/30 17:34
-	439	714/42.cccls.	USPAT; US-PGPUB	2003/12/30 18:09
-	1	714/42.cccls. and wavelength	USPAT; US-PGPUB	2003/12/30 18:11
-	2445	365/201.cccls.	USPAT; US-PGPUB	2003/12/30 18:11
-	6	365/201.cccls. and wavelength	USPAT; US-PGPUB	2003/12/30 18:15
-	744	438/17.cccls.	USPAT; US-PGPUB	2003/12/30 18:16
-	70	438/17.cccls. and wavelength	USPAT; US-PGPUB	2003/12/30 18:44

-		5	("4967152" "5030908" "5150043" "5508627" "5963783") .PN. 6184046.URPN.	USPAT	2003/12/30 18:27
-		0		USPAT	2003/12/30 18:29
-		13	"4929081"	USPAT; US-PGPUB	2003/12/30 18:44